

SDLS087

SN5426, SN54LS26, SN7426, SN74LS26 QUADRUPLE 2-INPUT HIGH-VOLTAGE INTERFACE POSITIVE-NAND GATES

DECEMBER 1983—REVISED MARCH 1988

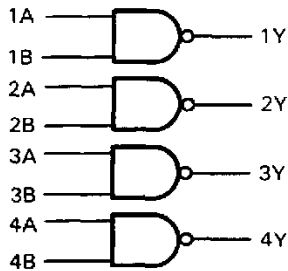
- For Driving Low-Threshold-Voltage MOS Inputs

description

These 2-input open-collector NAND gates feature high-output voltage ratings for interfacing with low-threshold-voltage MOS logic circuits or other 12-volt systems. Although the output is rated to withstand 15 volts, the V_{CC} terminal is connected to the standard 5-volt source.

The SN5426 and SN54LS26 are characterized for operation over the full military temperature range of -55°C to 125°C . The SN7426 and SN74LS26 are characterized for operation from 0°C to 70°C .

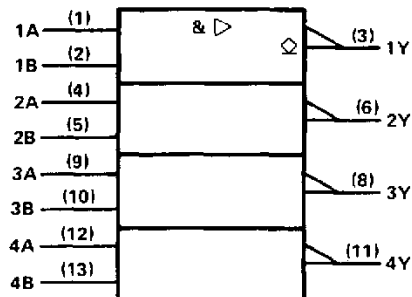
logic diagram



positive logic

$$Y = \overline{AB}$$

logic symbol†

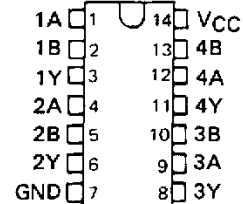


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

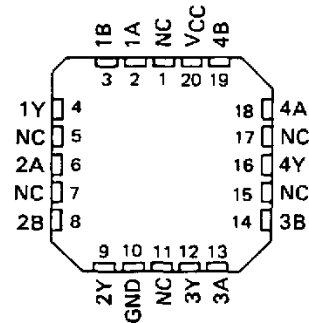
SN5426 . . . J PACKAGE
SN54LS26 . . . J OR W PACKAGE
SN7426 . . . N PACKAGE
SN74LS26 . . . D OR N PACKAGE

(TOP VIEW)



SN54LS26 . . . FK PACKAGE

(TOP VIEW)



NC - No internal connection

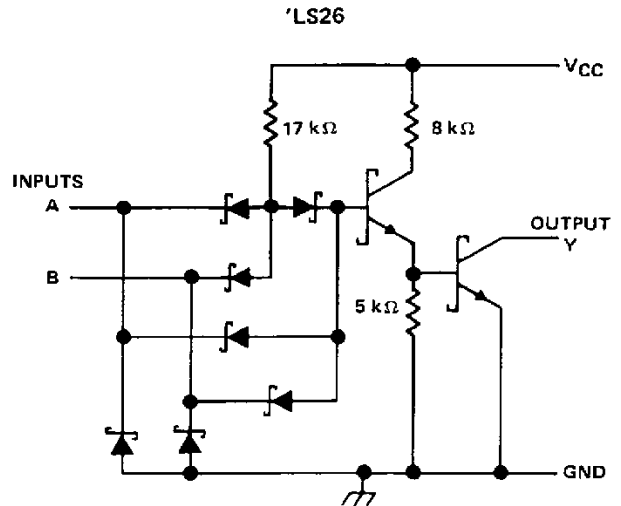
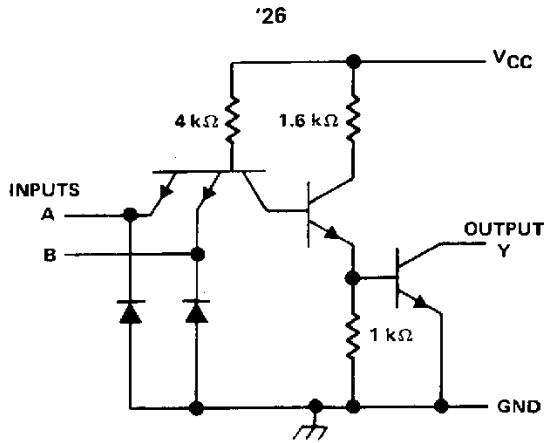
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TEXAS
INSTRUMENTS

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SN5426, SN54LS26, SNSN7426, SN74LS26
QUADRUPLE 2-INPUT
HIGH-VOLTAGE INTERFACE POSITIVE-NAND GATES

schematics



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage: '26	5.5 V
'LS26	7 V
Operating free-air temperature: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN54LS26, SN74LS26
QUADRUPLE 2-INPUT
HIGH-VOLTAGE INTERFACE POSITIVE-NAND GATES

recommended operating conditions

	SN54LS26			SN74LS26			UNIT		
	MIN	NOM	MAX	MIN	NOM	MAX			
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V		
V _{IH} High-level input voltage	2			2			V		
V _{IL} Low-level input voltage	0.7			0.8			V		
V _{OH} High-level output voltage	15			15			V		
I _{OL} Low-level output current	4			8			mA		
T _A Operating free-air temperature	- 55			125			0	70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN54LS26		SN74LS26		UNIT
		MIN	TYP‡	MAX	MIN	
V _{IK}	V _{CC} = MIN, I _I = - 18 mA	- 1.5		- 1.5		V
I _{OH}	V _{CC} = MIN, V _{IL} = MAX, V _{OH} = 12 V	50		50		μA
	V _{CC} = MIN, V _{IL} = MAX, V _{OH} = 15 V	1		1		mA
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 4 mA	0.25	0.4	0.25	0.4	V
	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 8 mA			0.35	0.5	
I _I	V _{CC} = MAX, V _I = 7 V	0.1		0.1		mA
I _{IH}	V _{CC} = MAX, V _{IH} = 2.7 V	20		20		μA
I _{IL}	V _{CC} = MAX, V _{IL} = 0.4 V	- 0.4		- 0.4		mA
I _{CCH}	V _{CC} = MAX, V _I = 0	0.8	1.6	0.8	1.6	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V	2.4	4.4	2.4	4.4	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	A or B	Y	R _L = 2 kΩ, C _L = 15 pF	17	32		ns
t _{PHL}				15	28		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



**SN5426, SN7426
 QUADRUPLE 2-INPUT
 HIGH-VOLTAGE INTERFACE POSITIVE-NAND GATES**

recommended operating conditions

	SN5426			SN7426			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage	0.8			0.8			V
V _{OH} High-level output voltage	15			15			V
I _{OL} Low-level output current	16			16			mA
T _A Operating free-air temperature	- 55			125			0 70 °C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN5426			SN7426			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -12 mA	-1.5			-1.5			V
I _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, V _{OH} = 12 V				50			μA
	V _{CC} = MIN, V _{IL} = 0.7 V, V _{OH} = 12 V	50						
	V _{CC} = MIN, V _{IL} = 0.8 V, V _{OH} = 15 V				1			mA
	V _{CC} = MIN, V _{IL} = 0.7 V, V _{OH} = 15 V	1						
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 16 mA	0.4			0.4			V
I _I	V _{CC} = MAX, V _I = 5.5 V	1			1			mA
I _{IH}	V _{CC} = MAX, V _I = 2.4 V	40			40			μA
I _{IL}	V _{CC} = MAX, V _I = 0.4 V	-1.6			-1.6			mA
I _{CCH}	V _{CC} = MAX, V _I = 0	4 8			4 8			mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V	12 22			12 22			mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	A or B	Y	R _L = 1 kΩ, C _L = 15 pF	16		24	ns
t _{PHL}				11		17	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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